MC14521B

24-Stage Frequency Divider

The MC14521B consists of a chain of 24 flip–flops with an input circuit that allows three modes of operation. The input will function as a crystal oscillator, an RC oscillator, or as an input buffer for an external oscillator. Each flip–flop divides the frequency of the previous flip–flop by two, consequently this part will count up to $2^{24} = 16{,}777{,}216$. The count advances on the negative going edge of the clock. The outputs of the last seven–stages are available for added flexibility.

Features

- All Stages are Resettable
- Reset Disables the RC Oscillator for Low Standby Power Drain
- RC and Crystal Oscillator Outputs Are Capable of Driving External Loads
- Test Mode to Reduce Test Time
- V_{DD}' and V_{SS}' Pins Brought Out on Crystal Oscillator Inverter to Allow the Connection of External Resistors for Low–Power Operation
- Supply Voltage Range = 3.0 Vdc to 18 Vdc
- Capable of Driving Two Low–Power TTL Loads or One Low–Power Schottky TTL Load over the Rated Temperature Range
- These Devices are Pb–Free and are RoHS Compliant
- NLV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC–Q100 Qualified and PPAP Capable

MAXIMUM RATINGS (Voltages Referenced to V_{SS})

Parameter	Symbol	Value	Unit
DC Supply Voltage Range	V_{DD}	−0.5 to +18.0	V
Input or Output Voltage Range (DC or Transient)	V_{in}, V_{out}	−0.5 to V_{DD} +0.5	V
Input or Output Current (DC or Transient) per Pin	I_{in}, I_{out}	±10	mA
Power Dissipation, per Package (Note 1)	P_D	500	mW
Ambient Temperature Range	T_A	−55 to +125	°C
Storage Temperature Range	T_{stg}	−65 to +150	°C
Lead Temperature (8–Second Soldering)	T_L	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1. Temperature Derating: Plastic “P and D/DW” Packages: – 7.0 mW/°C From 65°C To 125°C

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high–impedance circuit. For proper operation, V_{in} and V_{out} should be constrained to the range $V_{SS} \le (V_{in}$ or $V_{out}) \le V_{DD}$.

Unused inputs must always be tied to an appropriate logic voltage level (e.g., either V_{SS} or V_{DD}). Unused outputs must be left open.

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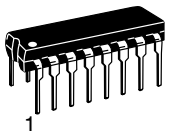
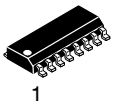
MARKING DIAGRAMS



PDIP–16
P SUFFIX
CASE 648



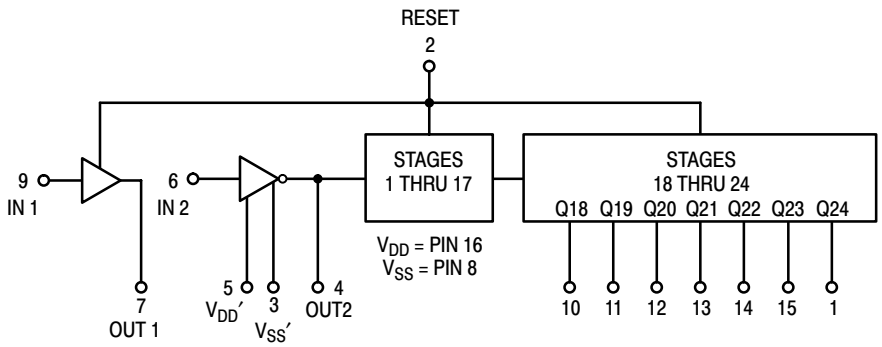
SOIC–16
D SUFFIX
CASE 751B

A	= Assembly Location
WL, L	= Wafer Lot
YY, Y	= Year
WW, W	= Work Week
G	= Pb–Free Package

ORDERING INFORMATION

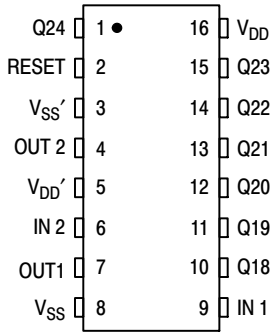
See detailed ordering and shipping information in the package dimensions section on page 2 of this data sheet.

BLOCK DIAGRAM



Output	Count Capacity
Q18	2^{18} = 262,144
Q19	2^{19} = 524,288
Q20	2^{20} = 1,048,576
Q21	2^{21} = 2,097,152
Q22	2^{22} = 4,194,304
Q23	2^{23} = 8,388,608
Q24	2^{24} = 16,777,216

PIN ASSIGNMENT



ORDERING INFORMATION

Device	Package	Shipping†
MC14521BCPG	PDIP−16 (Pb−Free)	500 Units / Rail
MC14521BDG	SOIC−16 (Pb−Free)	48 Units / Rail
NLV14521BDG*		
MC14521BDR2G	SOIC−16 (Pb−Free)	2500 / Tape & Reel
NLV14521BDR2G*		

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

*NLV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC−Q100 Qualified and PPAP Capable.

ELECTRICAL CHARACTERISTICS (Voltages Referenced to V_{SS})

Characteristic	Symbol	V_{DD} Vdc	– 55°C Min	– 55°C Max	25°C Min	25°C Typ (Note 2)	25°C Max	125°C Min	125°C Max	Unit
Output Voltage "0" Level V_{in} = V_{DD} or 0	V_{OL}	5.0 10 15	– – –	0.05 0.05 0.05	– – –	0 0 0	0.05 0.05 0.05	– – –	0.05 0.05 0.05	Vdc
"1" Level V_{in} = 0 or V_{DD}	V_{OH}	5.0 10 15	4.95 9.95 14.95	– – –	4.95 9.95 14.95	5.0 10 15	– – –	4.95 9.95 14.95	– – –	Vdc
Input Voltage "0" Level (V_O = 4.5 or 0.5 Vdc) (V_O = 9.0 or 1.0 Vdc) (V_O = 13.5 or 1.5 Vdc)	V_{IL}	5.0 10 15	– – –	1.5 3.0 4.0	– – –	2.25 4.50 6.75	1.5 3.0 4.0	– – –	1.5 3.0 4.0	Vdc
"1" Level (V_O = 0.5 or 4.5 Vdc) (V_O = 1.0 or 9.0 Vdc) (V_O = 1.5 or 13.5 Vdc)	V_{IH}	5.0 10 15	3.5 7.0 11	– – –	3.5 7.0 11	2.75 5.50 8.25	– – –	3.5 7.0 11	– – –	Vdc
Output Drive Current (V_{OH} = 4.5 Vdc) Source (V_{OH} = 9.0 Vdc) Pin 4 (V_{OH} = 13 Vdc)	I_{OH}	5.0 10 15	– 0.25 – 0.62 – 1.8	– – –	– 0.2 – 0.5 – 1.5	– 0.36 – 0.9 – 3.5	– – –	– 0.14 – 0.35 – 1.1	– – –	mAdc
(V_{OH} = 2.5 Vdc) Source (V_{OH} = 4.6 Vdc) Pins 1, 7, 10, (V_{OH} = 9.5 Vdc) 11, 12, 13, 14 (V_{OH} = 13.5 Vdc) and 15		5.0 5.0 10 15	– 3.0 – 0.64 – 1.6 – 4.2	– – – –	– 2.4 – 0.51 – 1.3 – 3.4	– 4.2 – 0.88 – 2.25 – 8.8	– – – –	– 1.7 – 0.36 – 0.9 – 2.4	– – – –	mAdc
(V_{OL} = 0.4 Vdc) Sink (V_{OL} = 0.5 Vdc) (V_{OL} = 1.5 Vdc)	I_{OL}	5.0 10 15	0.64 1.6 4.2	– – –	0.51 1.3 3.4	0.88 2.25 8.8	– – –	0.36 0.9 2.4	– – –	mAdc
Input Current	I_{in}	15	–	± 0.1	–	±0.00001	± 0.1	–	± 1.0	μAdc
Input Capacitance (V_{in} = 0)	C_{in}	–	–	–	–	5.0	7.5	–	–	pF
Quiescent Current (Per Package)	I_{DD}	5.0 10 15	– – –	5.0 10 20	– – –	0.005 0.010 0.015	5.0 10 20	– – –	150 300 600	μAdc
Total Supply Current (Note 3, 4) (Dynamic plus Quiescent, Per Package) (C_L = 50 pF on all outputs, all buffers switching)	I_T	5.0 10 15	I_T = (0.42 μA/kHz) f + I_{DD} I_T = (0.85 μA/kHz) f + I_{DD} I_T = (1.40 μA/kHz) f + I_{DD}							μAdc

2. Data labelled "Typ" is not to be used for design purposes but is intended as an indication of the IC's potential performance.
3. The formulas given are for the typical characteristics only at 25°C.
4. To calculate total supply current at loads other than 50 pF: $I_T(C_L) = I_T(50\ pF) + (C_L - 50)$ Vfk where: I_T is in μA (per package), C_L in pF, V = ($V_{DD} - V_{SS}$) in volts, f in kHz is input frequency, and k = 0.003.

SWITCHING CHARACTERISTICS (Note 5) (C_L = 50 pF, T_A = 25°C)

Characteristic	Symbol	V_{DD} Vdc	Min	Typ (Note 6)	Max	Unit
Output Rise and Fall Time (Counter Outputs)	t_{TLH}, t_{THL}					ns
t_{TLH}, t_{THL} = (1.5 ns/pF) C_L + 25 ns		5.0	–	100	200	
t_{TLH}, t_{THL} = (0.75 ns/pF) C_L + 12.5 ns		10	–	50	100	
t_{TLH}, t_{THL} = (0.55 ns/pF) C_L + 12.5 ns		15	–	40	80	
Propagation Delay Time	t_{PHL}, t_{PLH}					μs
Clock to Q18						
t_{PHL}, t_{PLH} = (1.7 ns/pF) C_L + 4415 ns		5.0	–	4.5	9.0	
t_{PHL}, t_{PLH} = (0.66 ns/pF) C_L + 1667 ns		10	–	1.7	3.5	
t_{PHL}, t_{PLH} = (0.5 ns/pF) C_L + 1275 ns		15	–	1.3	2.7	
Clock to Q24						
t_{PHL}, t_{PLH} = (1.7 ns/pF) C_L + 5915 ns		5.0	–	6.0	12	
t_{PHL}, t_{PLH} = (0.66 ns/pF) C_L + 2167 ns		10	–	2.2	4.5	
t_{PHL}, t_{PLH} = (0.5 ns/pF) C_L + 1675 ns		15	–	1.7	3.5	
Propagation Delay Time	t_{PHL}					ns
Reset to Q_n						
t_{PHL} = (1.7 ns/pF) C_L + 1215 ns		5.0	–	1300	2600	
t_{PHL} = (0.66 ns/pF) C_L + 467 ns		10	–	500	1000	
t_{PHL} = (0.5 ns/pF) C_L + 350 ns		15	–	375	750	
Clock Pulse Width	$t_{WH(cl)}$	5.0	385	140	–	ns
		10	150	55	–	
		15	120	40	–	
Clock Pulse Frequency	f_{cl}	5.0	–	3.5	2.0	MHz
		10	–	9.0	5.0	
		15	–	12	6.5	
Clock Rise and Fall Time	t_{TLH}, t_{THL}	5.0	–	–	15	μs
		10	–	–	5.0	
		15	–	–	4.0	
Reset Pulse Width	$t_{WH(R)}$	5.0	1400	700	–	ns
		10	600	300	–	
		15	450	225	–	
Reset Removal Time	t_{rem}	5.0	30	– 200	–	ns
		10	0	– 160	–	
		15	– 40	– 110	–	

5. The formulas given are for the typical characteristics only at 25°C.
6. Data labelled “Typ” is not to be used for design purposes but is intended as an indication of the IC’s potential performance.

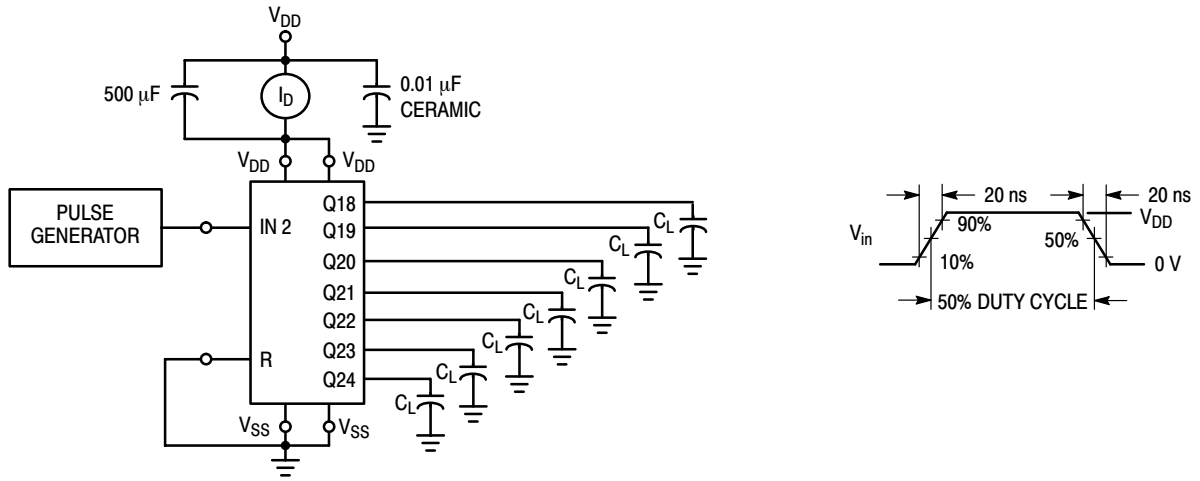


Figure 1. Power Dissipation Test Circuit and Waveform

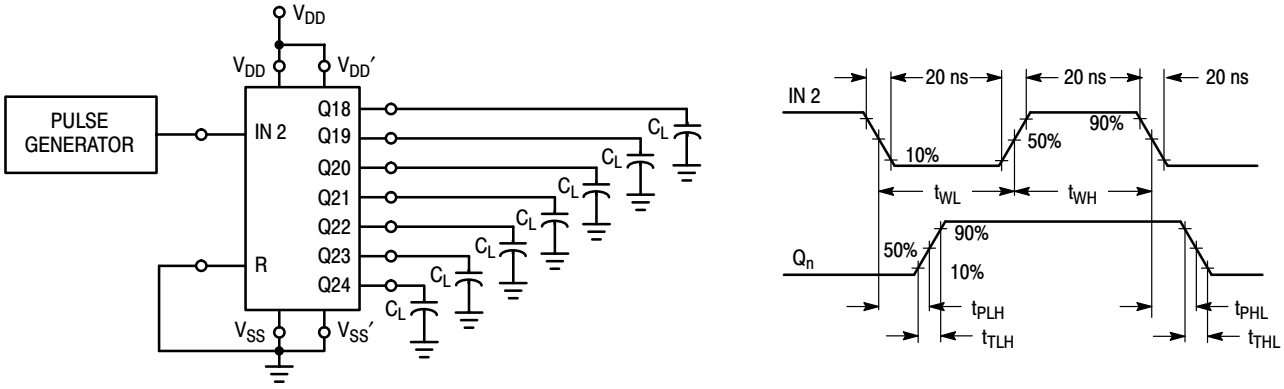
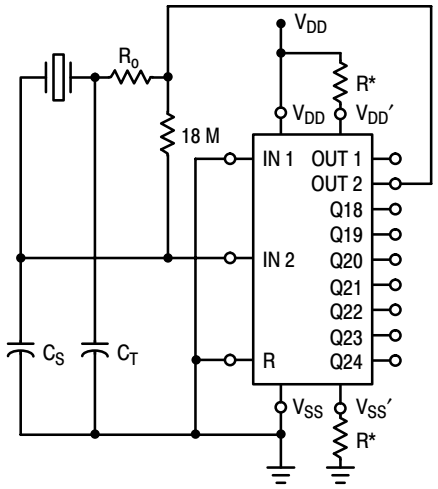


Figure 2. Switching Time Test Circuit and Waveforms



*Optional for low power operation,
10 kΩ ≤ R ≤ 70 kΩ.

Figure 3. Crystal Oscillator Circuit

Characteristic	500 kHz Circuit	50 kHz Circuit	Unit
Crystal Characteristics			
Resonant Frequency	500	50	kHz
Equivalent Resistance, R_S	1.0	6.2	kΩ
External Resistor/Capacitor Values			
R_o	47	750	kΩ
C_T	82	82	pF
C_S	20	20	pF
Frequency Stability			
Frequency Change as a Function of V_{DD} (T_A = 25°C)			
V_{DD} Change from 5.0 V to 10 V	+ 6.0	+ 2.0	ppm
V_{DD} Change from 10 V to 15 V	+ 2.0	+ 2.0	ppm
Frequency Change as a Function of Temperature (V_{DD} = 10 V)			
T_A Change from − 55°C to + 25°C	− 4.0	− 2.0	ppm
MC14521 only	+ 100	+ 120	ppm
Complete Oscillator*			
T_A Change from + 25°C to + 125°C	− 2.0	− 2.0	ppm
MC14521 only	− 160	− 560	ppm
Complete Oscillator*			

*Complete oscillator includes crystal, capacitors, and resistors.

Figure 4. Typical Data for Crystal Oscillator Circuit

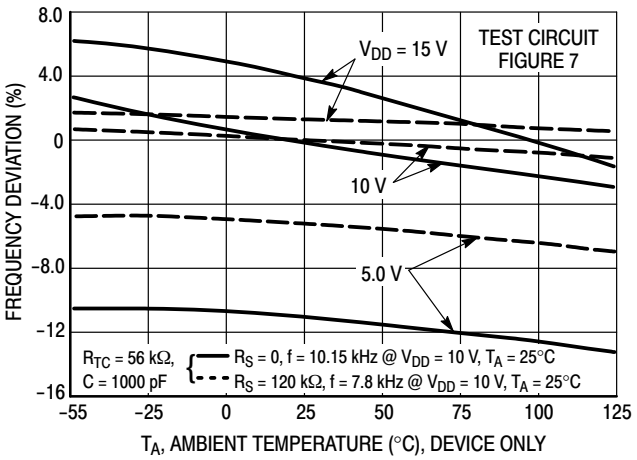


Figure 5. RC Oscillator Stability

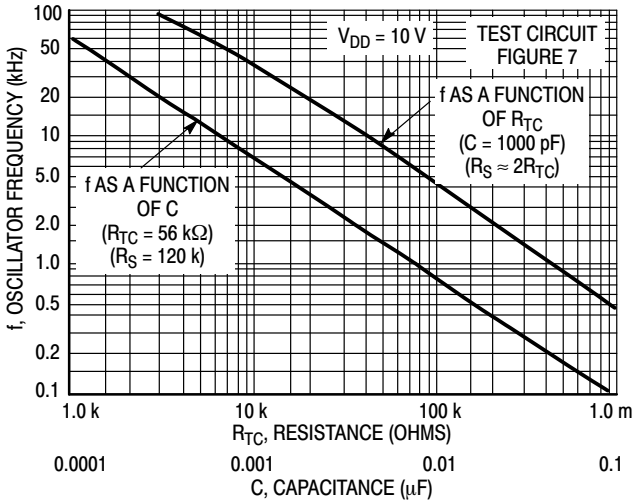


Figure 6. RC Oscillator Frequency as a Function of R_{TC} and C

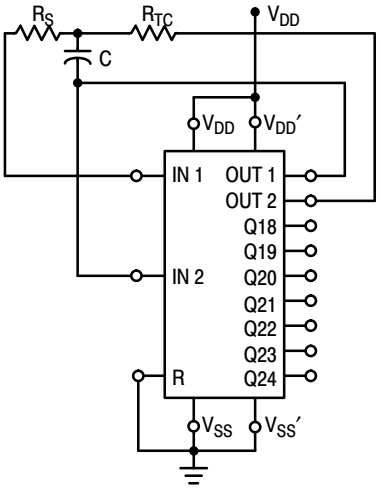


Figure 7. RC Oscillator Circuit

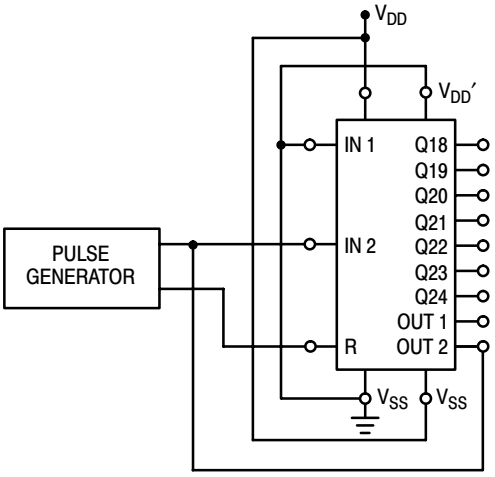


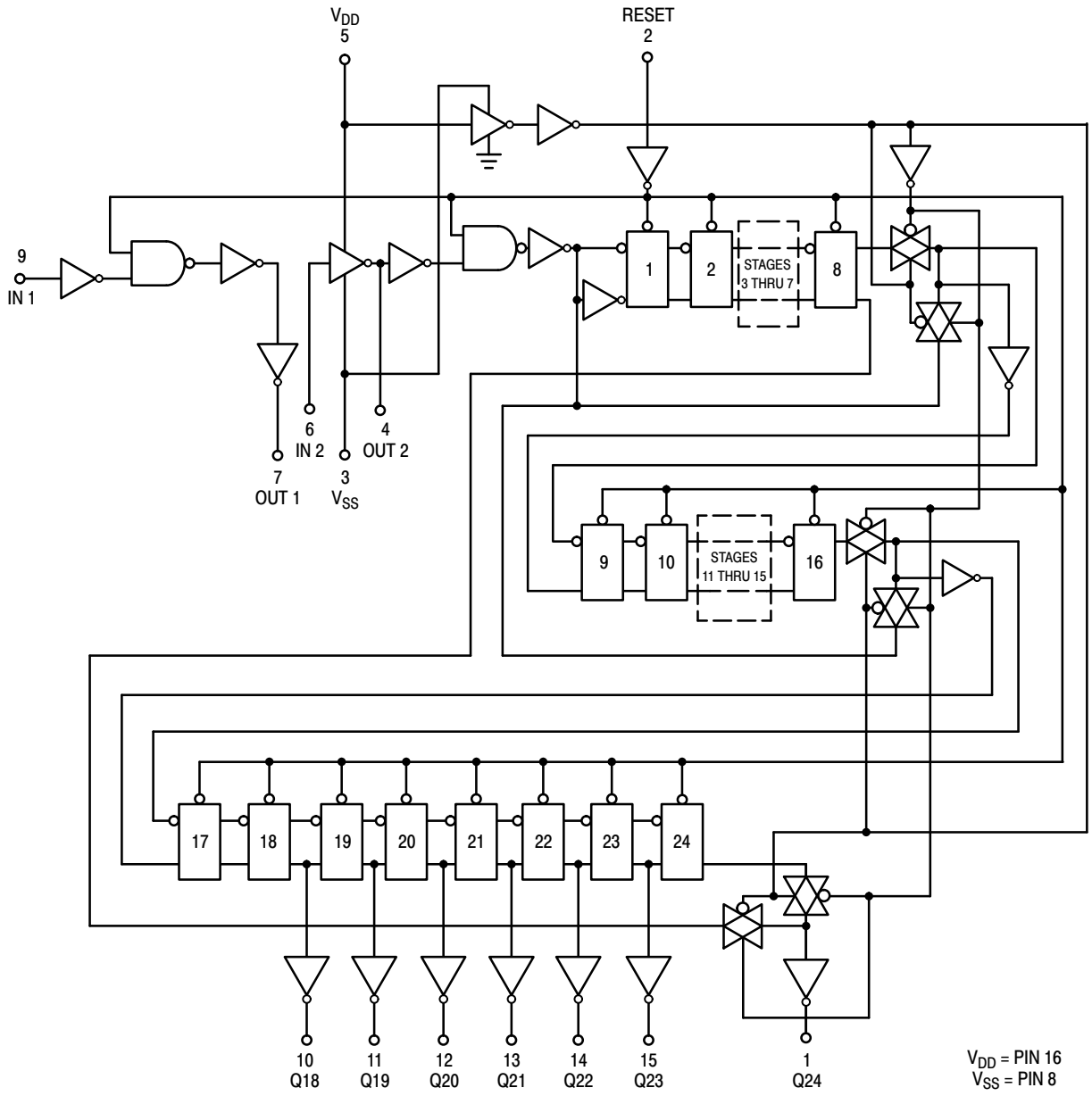
Figure 8. Functional Test Circuit

FUNCTIONAL TEST SEQUENCE

A test function (see Figure 8) has been included for the reduction of test time required to exercise all 24 counter stages. This test function divides the counter into three 8−stage sections, and 255 counts are loaded in each of the 8−stage sections in parallel. All flip−flops are now at a logic "1". The counter is now returned to the normal 24−stages in series configuration. One more pulse is entered into Input 2 (In 2) which will cause the counter to ripple from an all "1" state to an all "0" state.

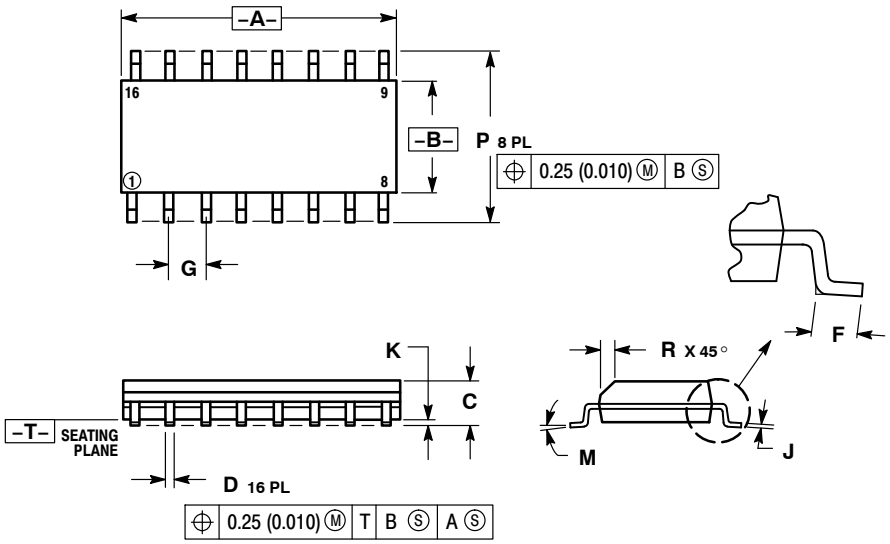
Inputs		Outputs				Comments
Reset	In 2	Out 2	V_{SS}'	V_{DD}'	Q18 thru Q24	Counter is in three 8−stage sections in parallel mode Counter is reset. In 2 and Out 2 are connected together.
1	0	0	V_{DD}	GND	0	
0	1	1				First "0" to "1" transition on In 2, Out 2 node.
	0 1 – – –	0 1 – – –				255 "0" to "1" transitions are clocked into this In 2, Out 2 node.
	1	1			1	The 255th "0" to "1" transition.
	0 0	0 0			1 1	
	1	0	GND		1	Counter converted back to 24−stages in series mode.
	1	0		V_{DD}	1	Out 2 converts back to an output.
	0	1			0	Counter ripples from an all "1" state to an all "0" stage.

LOGIC DIAGRAM



PACKAGE DIMENSIONS

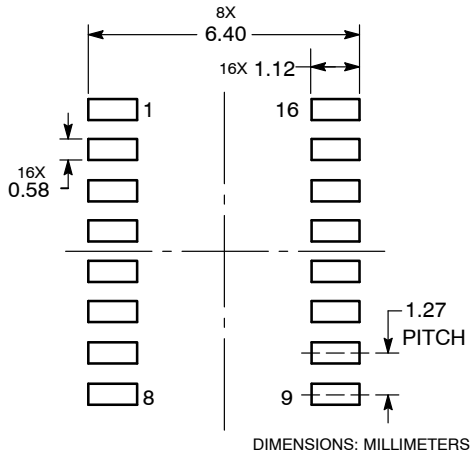
SOIC−16
CASE 751B−05
ISSUE K



NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER.
3. DIMENSIONS A AND B DO NOT INCLUDE MOLD PROTRUSION.
4. MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
5. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
A	9.80	10.00	0.386	0.393
B	3.80	4.00	0.150	0.157
C	1.35	1.75	0.054	0.068
D	0.35	0.49	0.014	0.019
F	0.40	1.25	0.016	0.049
G	1.27 BSC		0.050 BSC	
J	0.19	0.25	0.008	0.009
K	0.10	0.25	0.004	0.009
M	0°	7°	0°	7°
P	5.80	6.20	0.229	0.244
R	0.25	0.50	0.010	0.019

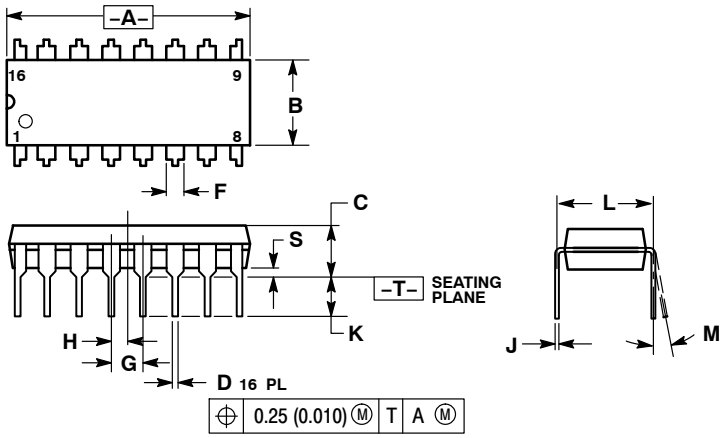
SOLDERING FOOTPRINT



DIMENSIONS: MILLIMETERS

PACKAGE DIMENSIONS

PDIP−16
CASE 648−08
ISSUE T



NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: INCH.
3. DIMENSION L TO CENTER OF LEADS WHEN FORMED PARALLEL.
4. DIMENSION B DOES NOT INCLUDE MOLD FLASH.
5. ROUNDED CORNERS OPTIONAL.

	INCHES		MILLIMETERS	
DIM	MIN	MAX	MIN	MAX
A	0.740	0.770	18.80	19.55
B	0.250	0.270	6.35	6.85
C	0.145	0.175	3.69	4.44
D	0.015	0.021	0.39	0.53
F	0.040	0.70	1.02	1.77
G	0.100 BSC		2.54 BSC	
H	0.050 BSC		1.27 BSC	
J	0.008	0.015	0.21	0.38
K	0.110	0.130	2.80	3.30
L	0.295	0.305	7.50	7.74
M	0 °	10 °	0 °	10 °
S	0.020	0.040	0.51	1.01

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MC14521B/D